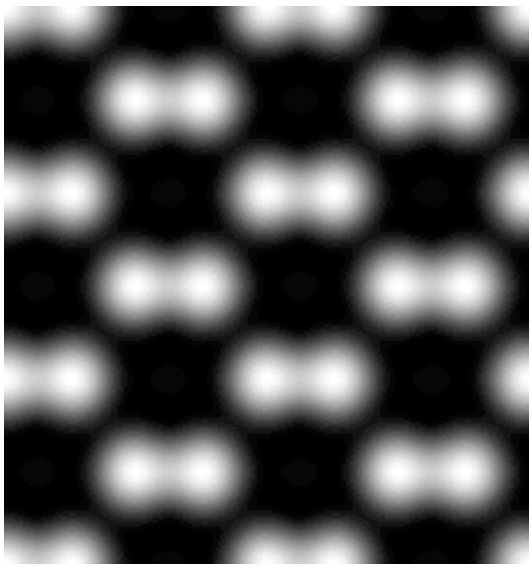
Optional Function

STEM

for *MacHREM™ / WinHREM™*

Scanning Transmission Electron Microscope Image Simulation Program



Simulated HAADF image for GaAs [011]

This optional function adds the capability for simulating high-resolution scanning transmission electron microscope images to the ***MacHREM™ /WinHREM™*** program suite. Using this program you can simulate bright-field images, dark-field images and high-angle annular dark-field (HAADF) images by using the FFT multislice technique on a personal computer.

- User Friendly Graphical Interface
  Even a novice user can easily generate his/her data and perform computation.
- Reliable and Efficient Algorithm
  Dynamical electron interaction is efficiently estimated by using the FFT multislice technique including an absorption potential.
- High Quality Image Output
  All images are generated with a standard image format of Windows/Mac OS. Therefore, high quality images can be printed from them, and they can be imported into another application.

Please Contact to:

HREM Research Inc.

14-48 Matsukazedai, Higashimatsuyama, 355-0055 JAPAN

TEL/FAX (81) 493-35-3919

email: support@hremresearch.com

Reference: K. Ishizuka: A practical approach for STEM image simulation based on the FFT multislice method, Ultramicroscopy 90 (2001) 71-83.